



Integrated Device Technology, Inc.
2975 Stender Way, Santa Clara, CA - 95054

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: **T0403-06** DATE: 3/23/2004
Product Affected: IDT82P2288BB, IDT82P2284BB

MEANS OF DISTINGUISHING CHANGED DEVICES:

- Product Mark
- Back Mark "ZB" prefix
- Date Code
- Other

Date Effective: 6/23/2004

Contact: Bimla Paul
Title: Quality Assurance Manager
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Attachment: Yes No

Samples: Available on request.

DESCRIPTION AND PURPOSE OF CHANGE:

- Die Technology
- Wafer Fabrication Process
- Assembly Process
- Equipment
- Material
- Testing
- Manufacturing Site
- Data Sheet
- Other

Please see attachment for detail of change.

RELIABILITY/QUALIFICATION SUMMARY:

Please see attachment for qualification summary.

CUSTOMER ACKNOWLEDGMENT OF RECEIPT:

IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.
IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: _____

Approval for shipments prior to effective date.

Name/Date: _____

E-Mail Address: _____

Title: _____

Phone# /Fax# : _____

CUSTOMER COMMENTS: _____

IDT ACKNOWLEDGMENT OF RECEIPT:

RECD. BY: _____

DATE: _____



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ATTACHMENT - PCN #: T0403-06

PCN Type: Die Revision and datasheet change
Datasheet Change: Yes
Detail of Change: The new die revision is "ZB", and LOS status indication option for REFA_OUT and REFB_OUT pins has been added. A register setting REFH_LOS has been added for selecting LOS status indication. There is no change in device performance. Customers are not required to make any changes to use the new revision. Please visit the following URL for a detailed summary of changes to the product datasheets:

IDT82P2288BB <http://www1.idt.com/pcms/getDoc.taf?docID=9612>
 IDT82P2284BB <http://www1.idt.com/pcms/getDoc.taf?docID=9616>

Devices providing REFH_LOS register setting can be identified by the top mark **date code**:

| Revision | Date Code Mark |
|-------------|----------------|
| Z (current) | Zyyww |
| ZB (new) | ZByyww |

Note: yy = last two digits of the year
ww = workweek

After the PCN effective date of 06/23/04, IDT may ship either the current revision (Z) or the new revision (ZB), unless otherwise requested.

Qualification Data

Qualification Plan: QFI-03-12R1

Test Vehicle: IDT82P2288BB

| Test Description/Condition | Test Methods | Required SS / # Fails | Qual Test Results | |
|--|-----------------------------|-----------------------|-------------------|-----------------------|
| | | | Lot # 1 | Lot # 2 |
| Life Test (+125°C, 1000 hrs) | MIL-STD-883, Method 1005 | 77 / 0 | 77 / 0 | 77 / 0 ^[1] |
| Latch-Up Immunity (+ - I and V stress, + - 100 mA Trigger) | EIA/JESD 78 | 10 / 0 | 10 / 0 | N/A |
| ESD Human Body Model (2000V) | MIL-STD-883, Method 3015 | 3 / 0 | 3 / 0 | N/A |
| ESD Charge Device Model (500V) | JESD22-C101 | 3 / 0 | 3 / 0 | N/A |
| Highly Accelerated Stress Test (HAST) (Biased, 130°C/85% RH, 100 hrs) | JESD-22-A110B | 45 / 0 | 45 / 0 | N/A |

Note:

[1] 168 hour Early Life readpoint data. 1000 hour readpoint data expected by April 30, 2004.